

G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems



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The PAC-G and the Large-Scale Instruments Characterisation Program

Wednesday, 9 December 2020 09:10 (10 minutes)

This pitch-presentation will focus on the large-scale instrument characterisation program of the IRT Nanoelec. It will introduce the idea of a center of expertise in radiation hardness testing based in Grenoble. It will also briefly mention de PAC-G, service platform of the program.

Presenter: CAPRIA, Ennio (IRT Nanoelec PAC-G)

Session Classification: Welcome session